

SEMITRONICS CORP.

64 Commercial Street, Freeport, N.Y. 11520
Phone: (516) 623-9400 • Fax. (516) 623-6954

SEF40604

POWER MOSFET

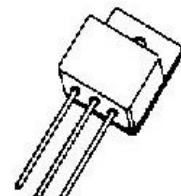
FEATURES

- Isolated Case
- Hermetically Sealed Package
- High dv/dt
- Low $R_{DS(on)}$ 0.35 Ohms
- Eutectic Die Attachment for Hi Reliability
- MIL STX Screening Available

APPLICATIONS

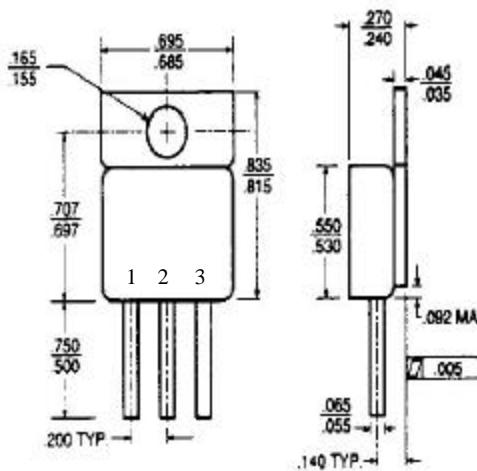
- High Reliability Power Supplies
- Switch Mode Power Supplies
- Battery Back-Up Supplies
- High Speed Power Switching

PACKAGE



TO-258AA

CASE OUTLINE



Pin 1: D Pin 2: S Pin 3: G

Absolute Maximum Ratings

Parameter	Maximum	Units
Continuous Drain Current I_D @ $T_c = 25^\circ C$,	20	A
Continuous Drain Current I_{AR} @ $T_c = 25^\circ C$	20	A
Pulse Drain Current I_{DM} @ $T_c = 25^\circ C$	80	A
Power Dissipation P_D @ $T_c = 25^\circ C$	300	W
Gate-to-Source Voltage V_{GS}	± 20	V
Peak Diode Recovery dv/dt	5.0	V/ns
Operating & Storage Temperature T_j & T_{STG}	-55 to +150	°C

Static @ T_j = 25°C (unless otherwise specified)

Parameter	Min.	Typ.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage V _{(BR)DSS}	600	—	—	V	V _{GS} = 0V, I _D = 250uA
Static Drain to Source On-Resistance R _{DS(on)}	—	—	0.35	Ω	V _{GS} = 10V, I _D = 10A
Gate Threshold Voltage V _{GS}	2.0	—	4.5	V	V _{DS} = V _{GS} , I _D = 4 mA
Drain-to-Source Leakage Current I _{DSS}	—	—	250	uA	V _{DS} = 480V, V _{GS} = 0V
	—	—	1000		V _{DS} = 480V, V _{GS} = 0V, T _j = 125°C
Gate-to-Source Forward Leakage I _{GSS}	—	—	100	nA	V _{GS} = 20V
Gate-to-Source Forward Leakage I _{GSS}	—	—	-100		V _{GS} = -20V

Dynamic @ T_j = 25°C (unless otherwise specified)

Parameter	Min.	Typ.	Max.	Units	Conditions
Forward Transconductance g _{fs}	11	18	—	S	V _{DS} = 10V, I _D = 10A pulse
Total Gate Charge Q _g	—	151	170	nC	I _D = 10A
Gate-to-Source Charge Q _{gs}	—	29	40		V _{DS} = 300V
Gate-to-Drain ("Miller") charge Q _{gd}	—	60	85		V _{GS} = 10V
Turn-on-Delay Time t _{d(on)}	—	20	40	ns	V _{GS} = 10V
Rise Time t _r	—	43	60		V _{DS} = 300V
Turn-Off-Delay Time t _{d(off)}	—	70	90		I _D = 10A
Fall time t _f	—	40	60		R _G = 2 Ohms
Input Capacitance C _{iss}	—	4500	—	pF	V _{GS} = 0V
Output Capacitance C _{oss}	—	420	—		V _{DS} = 25V
Reverse Transfer Capacitance C _{rss}	—	140	—		f = 1.0 MHZ

SEMITRONICS CORP.

SEF40604

Avalanche Characteristics

Parameter	Typ.	Max.	Units
Repetitive Avalanche Energy @ $T_C = 25^\circ C$ E_{AR}	—	30	mJ

Thermal Resistance

Parameter	Typ.	Max.	Units
Junction-to-case $R_{\theta JC}$	—	0.42	°C/W
Case-to-Sink, flat, Greased Surface $R_{\theta CS}$	0.25	—	

Diode Characteristics

Parameter	Min.	Typ.	Max.	Units	Conditions
Continuous Source Current I_S	—	—	20	A	$T_j = 25^\circ C$
Pulsed Source Current I_{SM}	—	—	80		
Diode Forward Voltage V_{SD}	—	—	1.5	V	$T_j = 25^\circ C, I_S=20A, V_{GS}=0V$
Reverse Recovery Time t_{rr}	—	—	250	ns	$T_j = 25^\circ C, I_F=20A$ $di/dt = 100A/\mu s$ $V_R = 100 V$
Reverse Recovery Charge Q_{rr}	—	1		uC	
Reverse Recovery Current I_{RM}		10		A	$T_j = 25^\circ C$

SEMITRONICS CORP.

SEF40604

Fig. 1 Output Characteristics

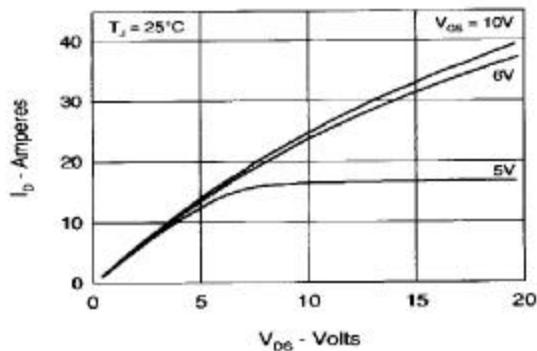


Fig. 3 $R_{DS(on)}$ vs. Drain Current

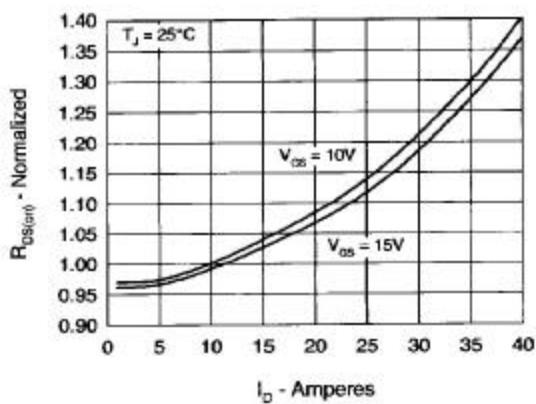


Fig. 5 Drain Current vs. Case Temperature

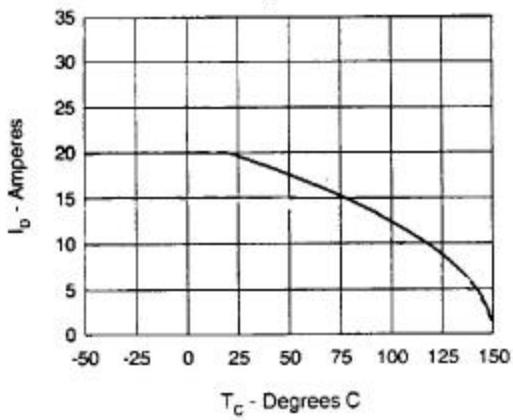


Fig. 2 Input Admittance

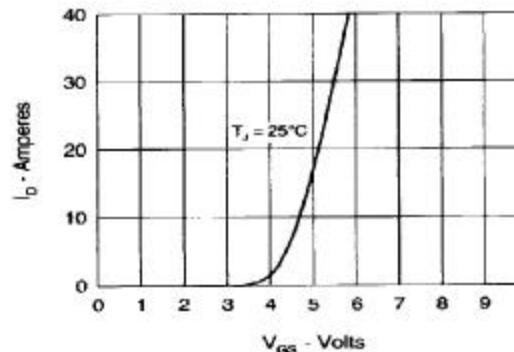


Fig. 4 Temperature Dependence of Drain to Source Resistance

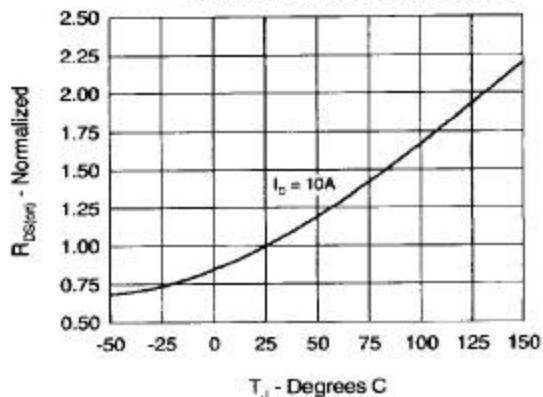


Fig. 6 Temperature Dependence of Breakdown and Threshold Voltage

